

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L10	319	(imag\$5 near4 (input\$5)) and ((decid\$5 or determin\$7 or discriminat\$5 or detect\$5 or judg\$6) near5 (pixel or pel or (picture adj3 element)) near5 color with (range or limit\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:54
L15	2	(Kenro near3 Hama).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:55
L17	86	(Akira near3 Murakawa).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:55
L18	244	(Keisuke near3 Hashimoto).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:56
L19	1	10 and 15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:56
L20	2	10 and 17	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:56
L21	1	10 and 18	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/29 14:56

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Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IIE CNF = IIE Conference, IEEE STD = IEEE Standard

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